

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1731	SERIAL NO. Unknown 09/932,003
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Cem Basceri	GROUP 2813
				FILING DATE Filed Herein 08/17/01	GROUP Unknown

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
jk	AA	5,256,455	10/26/93	Numasawa			
	AB	5,459,635	10/17/95	Tomozawa et al.			
	AC	5,596,214	01/21/97	Endo			
	AD	5,618,761	04/08/97	Eguchi et al.			
	AE	5,731,948	03/24/98	Yializis et al.			
	AF	5,776,254	07/07/98	Yuuki et al.			
	AG	5,783,253	07/21/98	Roh			
	AH	5,798,903	8/25/98	Dhote et al.			
	AI	6,043,526	3/28/00	Ochiai			
	AJ	6,046,345	04/04/00	Kadokura et al.			
jk	AK	6,078,492	06/20/00	Huang et al.			

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
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jk	AL	EP 0 855 735 A2	29.07.98	Europe (Applied Materials, Inc.)			
	AM	EP 0 957 522 A2	17.11.99	Europe (Matsushita Electric Industrial Co. Ltd.)			
	AN	WO 98/39497	09/11/98	WIPO (Simpson, et al.)			
	AO	0 474 140 A1	08/30/91	Europe (Kamiyama)			
	AP	WO 99/64645	12/16/99	WIPO (Narwankur, et al.)			

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
jk	AR	Steve Bilodeau et al., <i>Composition Dependence of the Dielectric Properties of MOCVD Ba,Sr,TiO₃</i> , pp. 1-21 (MRS Fall Meeting 12/01/94).
jk	AS	Steve M. Bilodeau et al., <i>MOCVD BST for High Density DRAM Applications</i> (Preprint for SEMICON/WEST 07/12/95), 2 pages.
	AT	Y-C Choi et al., Abstract, <i>Improvements of the Properties of Chemical-Vapor-Deposited (Ba,Sr)TiO₃ Films Through Use of a Seed Layer</i> , 36 JPN. J. APPL. PHYS. Pt. 1, No. 11, pp. 6824-6828 (1997)

EXAMINER 488	DATE CONSIDERED 12/21/01
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U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
y/s	AA	6,153,898	11/28/00	Watanabe et al.				
	AB	6,037,205	03/14/00	Huh, et al.				
	AC	5,470,398	11/28/95	Shibuya, et al.				
	AD	5,254,505	10/19/93	Kamiyama				
	AE	6,156,638	12/05/00	Agarwal et al.				
y/s	AF	6,165,834	12/26/00	Agarwal et al.				
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
y/s	AR		Chung Ming Chu et al., Abstract, <i>Electrical properties and crystal structure of (Ba,Sr)TiO₃ films prepared at low temperatures</i>					
			on a LaNiO ₃ electrode by radio-frequency magnetron, 70 APPLIED PHYSICS LETTERS No. 2, pp. 249-251 (1997).					
y/s	AS		Kazuhiro Eguchi et al., Abstract, <i>Chemical vapor deposition of (Ba,Sr)TiO₃ thin films for application in gigabit scale</i>					
			dynamic random access memories, 14 INTEGRATED FERROELECTRICS Nos. 1-4, Pt. 1, pp. 33-42 (1997).					
y/s	AT		Q.X. Jia et al., Abstract, <i>Structural and dielectric properties of Ba_{0.5}Sr_{0.5} thin films with an epi-RuO₂ bottom electrode.</i>					
			19 INTEGRATED FERROELECTRICS Nos. 1-4, pp. 111-119 (1998).					
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
yes	AR	Takaaki Kawahara et al., (Ba, Sr)TiO ₂ Films Prepared by Liquid Source Chemical Vapor Deposition on Ru Electrodes, 35 JPN. J.						
		APPL. PHYS. Pt. 1, No. 9B, pp. 4880, 4883 (1996).						
	AS	Rajesh Khamankar et al., A Novel Low-Temperature Process for High Dielectric Constant BST Thin Films for ULSI DRAM						
		Applications, Microelectronics Research Center, Univ. of Texas at Austin, TX (Undated), 2 pages.						
OK	AT	Yong Tae Kim et al., Abstract, Advantages of RuO ₂ bottom electrode in the dielectric and leakage characteristics of						
		(Ba,Sr)TiO ₂ capacitor, 35 JPN. J. APPL. PHYS. Pt. 1, No. 12A, pp. 6153-6156 (1996).						
EXAMINER		12/27/02			DATE CONSIDERED			yes
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y e r y y	AR		S.H. Paek et al., Abstract, <i>Characterization of MIS capacitor of BST thin films deposited on Si by RF magnetron sputtering</i> .				
			Ferroelectric Thin Films V. Symposium, San Francisco, CA, pp. 33-38 (April 7, 1995).				
	AS		N. Takeuchi et al., Abstract, <i>Effect of firing atmosphere on the cubic-hexagonal transition in Ba_{0.99}Sr_{0.01}TiO₃</i> , 98 NIPPON				
			SERAMIKKUSU KYOKAI GAKUJUTSU RONBUNSHI No. 8, pp. 836-839 (1990).				
AT		H. Yamaguchi, et al., Abstract, <i>Reactive coevaporation synthesis and characterization of SrTiO₃-BaTiO₃ thin films</i> , IEEE					
		International Symposium on Applications of Ferroelectrics, Greenville, SC, pp. 285-288 (August 2, 1992).					
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48 49 50	AR		S. Yamamichi et al., Abstract, <i>Ba + Sr/Ti ratio dependence of the dielectric properties for (Ba_{0.5})Sr_{0.5}TiO₃ thin films prepared by ion beam sputtering</i> , 64 APPLIED PHYSICS LETTERS No. 13, pp. 1644-1646 (1994).				
	AS		M. Yamamuka et al., Abstract, <i>Thermal-Desorption Spectroscopy of (Ba,Sr)TiO₃ Thin-Films Prepared by Chemical-Vapor-Deposition</i> ,				
		35 JPN. J. OF APPL. PHYS. Pt. 1, No. 2A, pp. 729-735 (1996).					
AT		Arui T., et al: "Preparation of SrTiO ₃ Films on 8-Inch Wafers. . ." Jap. Journal of Applied Physics. Vol. 35, No. 9B, Part 01, 09/01/96,					
		Pgs. 4875-4879.					
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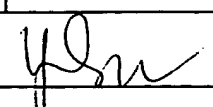
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<div style="font-size: 2em; font-weight: bold;">MOVE</div> <div style="font-size: 2em; font-weight: bold;">HERE</div>	AA	09/388,063	Agarwal et al.			August 30, 1999	
	AB	09/476,516	Basceri			January 3, 2000	
	AC	09/580,733	Basceri			May 26, 2000	
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<div style="font-size: 2em; font-weight: bold;">HERE</div>	AR		Kim, et al.: "Structural and Electrical Properties. . ." Applied Physics Letters, US, American Institute of Physics Vol. 65, No. 15, 10/10/94, Pgs. 1955 - 1957.
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jk	AA 5,834,060	11/98	Kawahara et al.				
	AB 5,972,430	10/99	DiMeo, Jr. et al.				
	AC 6,127,218	10/00	Kang				
	AD 6,277,436 B1	08/01	Stauf et al.				
	AE 6,245,652 B1	06/01	Gardner et al.				
jc	AF 6,126,753	10/00	Shinriki et al.				
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AR		Basceri, Cem et al., "The Dielectric Response as a Function of Temperature and Film Thickness of Fiber-Textured (Ba,Sr)TiO ₃ Thin Films Grown by Chemical Vapor Deposition", J. Appl. Phys. 82(5), Sept. 1, 1997, pp. 2497-2504.					
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AA	App. SN 09/652,907 (as filed and amended)		C. Basceri et al.			08/31/00
AB	App. SN 09/776,217 (as filed and amended)		C. Basceri			02/02/01
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Sheet 1 of 2

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Form 609		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1731		SERIAL NO. 09/932,003	
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YA	AR		DISSERTATION: Basceri, Cem, "Electrical and Dielectric Properties of (Ba,Sr)TiO ₃ Thin Film Capacitors for Ultra High Density				
			Dynamic Random Access Memories", 1997, 171 pgs.				
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yq				5/1/03			
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Sheet 2 of 2

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MP	AA App. SN 09/905,286 (as filed and amended)		C. Basceri et al.			07/13/01
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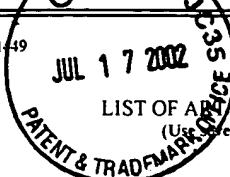
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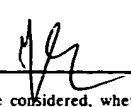
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4	AA	6,238,734 B1	05/01	Senzaki et al.			RECEIVED JUL 23 2002 TECHNOLOGY CENTER 2800
	AB	6,146,907	11/00	Xiang et al.			
	AC	6,323,057 B1	11/01	Sone			
ML	AD	6,362,068 B1	03/02	Summerfelt et al.			
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